



Technische  
Universität  
Braunschweig



## Model-based Testing of Software Product Lines – Part II

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# Challenges of Testing variant-rich Software Systems

## Observations:

- Complex systems with many interacting functions and features
- Many system variants and versions
- Large rate of changes, in particular in agile development processes

## Consequences:

- Increasing testing effort
- Combinatorial explosion during integration and system testing
- Complete re-test in case of changes mostly infeasible



# Roadmap

- Describing and Managing Variant-rich Systems
- Testing Strategies for Software Product Lines
  - Sample-based Testing of SPLs
  - Regression-based Testing of SPLs
  - Family-based Testing of SPLs



# Describing and Managing Variant-rich Systems



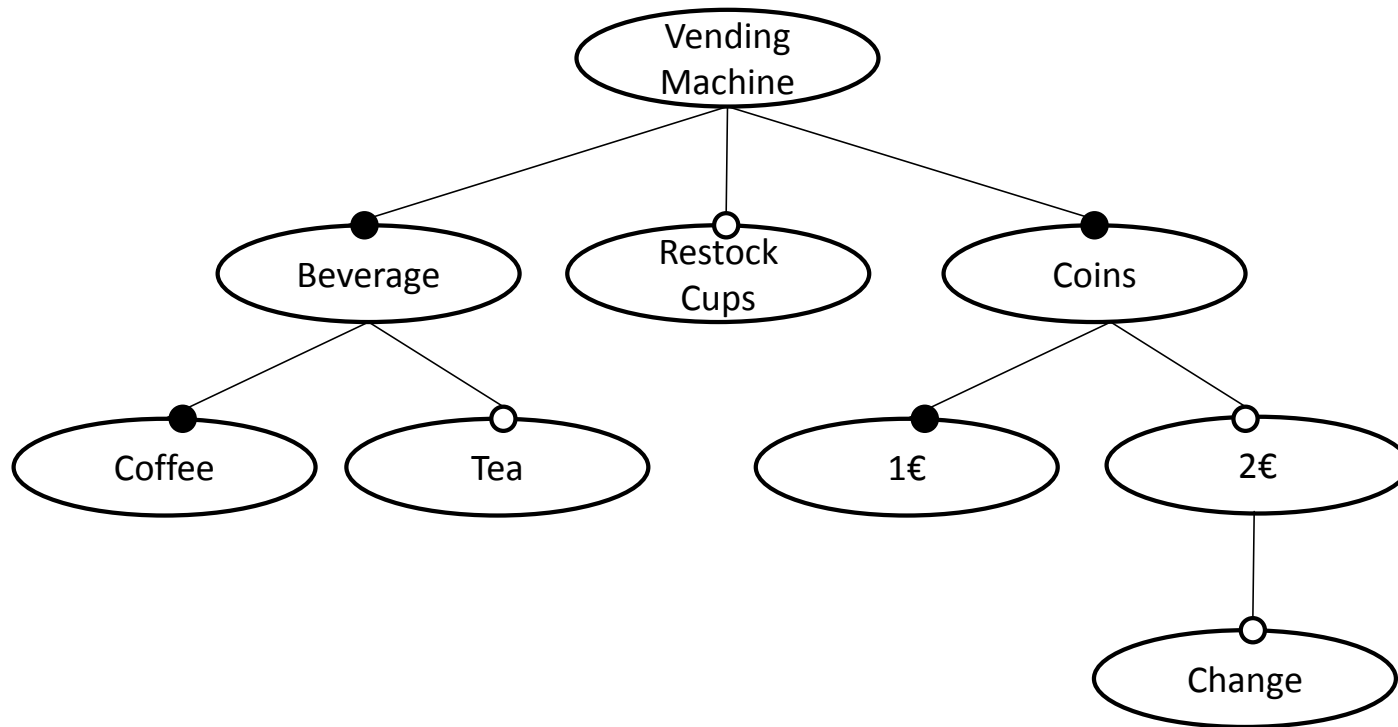
# Describing and Managing variant-rich Systems

- Variant-rich systems can be described as **Software Product Lines**.
- **SPLs** are systems, which have commonalities and variabilities between each other.
- A SPL consists of several **features** which are either **mandatory** or **optional**.
- There can be further constraints between features
  - Feature A excludes feature B
  - Feature A requires feature B
  - Feature A OR feature B has to be selected
  - ...
- How to describe and manage these features and there connections?



# Feature Models

- Kang et al. [Kang90] introduced **Feature-Models** as possibility to represent SPLs
- FMs are **tree-structures**, which represent features and their dependencies



# Feature Interactions

- A **feature** is a customer-visible product characteristic.
- Each feature in isolation satisfies its specification.
- If features are combined, the single specifications are violated. There are unwanted side effects.

→ **Feature Interaction!**



# Example: Combine Fire and Water Alarms



If there is fire, start sprinkling system.



If there is water, cut the main water line.



# Reasons for Feature Interactions

## Intended Feature Interactions:

- Communication via shared variables: one feature writes, another feature reads values.

## Unintended Feature Interactions:

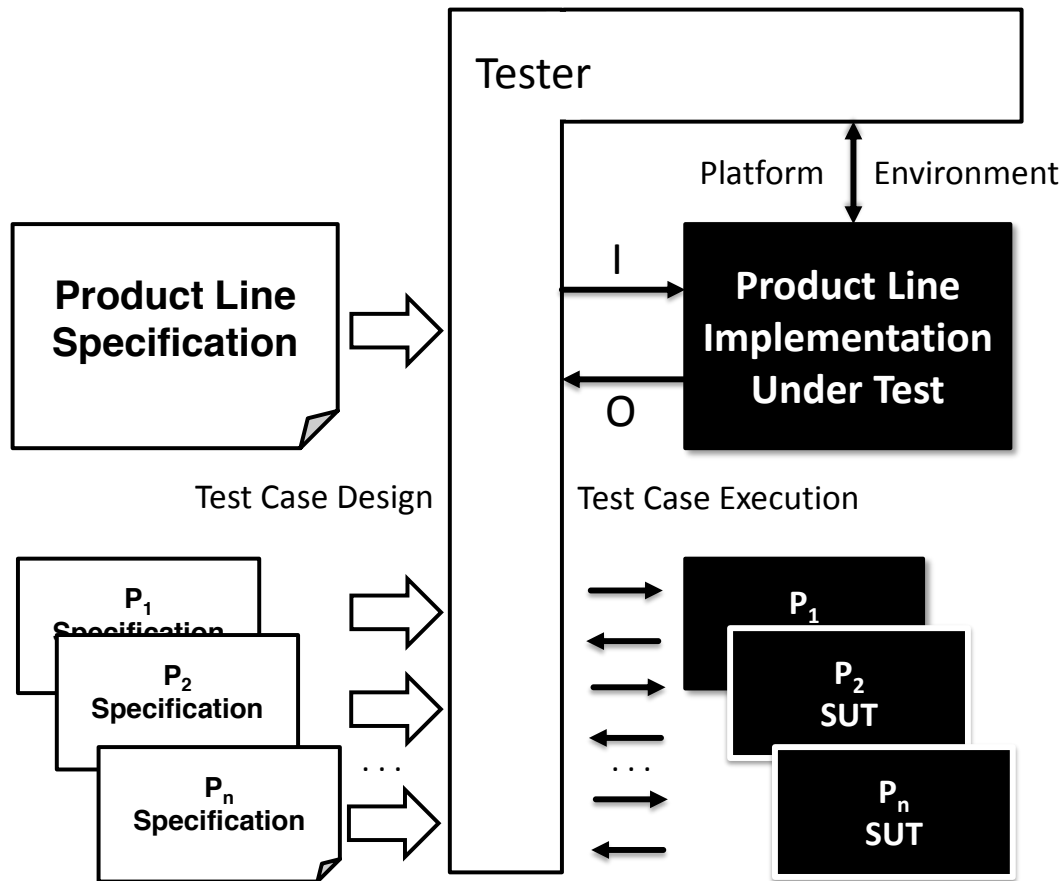
- Non-synchronized write access to shared resources, such as actuators, memory, shared variables, status flags

## In general, **uncritical**:

- Shared read access to resources, e.g., sensors

# SPL Testing Strategies

# Software Product Line Testing



# SPL Testing Strategies

## Sample-based SPL testing

- Selection of representative subsets from a large set of possible variants

## Regression-based SPL Testing:

- Reuse test cases and test results in order to efficiently test the selected variants

## Family-based SPL Testing:

- Derive test suite from a 150%-SPL test model

# Sample-based SPL Testing



# Process of Sample-based SPL Testing

- **Problem:** Number of test cases grows exponentially
- **Solution:** Combinatorial Interaction Testing (CIT)
  1. Create Feature Model
  2. Generate a subset of variants based on the FM, covering relevant combinations of features
  3. Apply single system testing to the selected variants
- Efficiency of t-wise Covering Arrays (CA)
  - 1-wise CA: 50% of all errors
  - 2-wise CA: 75% of all errors
  - 3-wise CA: 95% of all errors

➤ Trade-Off



# Set Covering Problem and CAs

- $S = \{a,b,c,d,e\}$  SPL features
- $M = \{\{a,b,c\}, \{b,d\}, \{c,d\}, \{d,e\}\}$  valid product configurations
- What is the optimal Covering Array?
- **Solution:**  $L = M_1 + M_4$  minimal CA
- **Precondition:** All valid product configurations already known
  - SAT-problem, which is NP-complete
  - Fortunately, we deal with realistic FMs
- Foundation of pairwise testing...

# First Solution by Chvátal (1979)

- **Idea of the algorithm:**

1. Set  $L = \emptyset$
2. If  $M_i = \emptyset, \forall i, i \in \{1, 2, \dots, n\}$  END.  
*ELSE find  $M'$ , where # of uncovered elements is max*
3. Add  $M'$  to  $L$  and replace elements in  $M_i$  by  $M_i - M'$
4. Goto Step 2



- **Worst Case:**  $M$  contains only subsets with different elements
- Best solution not guaranteed
- Adaptation for pairwise CA generation is easy!



# Adaptation to FMs and Improvements by the ICPL

```
input : arbitrary FM
output: t-wise covering array

1 S ← all t-tuples
2 while S ≠ ∅ do
3   k ← new and empty configuration
4   counter ← 0
5   foreach tuple p in S do
6     if FM is satisfiable with k ∪ p then
7       k ← k ∪ p
8       S ← S \ {p}
9       counter ← counter + 1
10  end
11 end
12 if counter > 0 then
13   L ← L ∪ (FM satisfy with {k})
14 end
15 if counter < # of features in FM then
16   foreach tuple p in S do
17     if FM not satisfiable with p then
18       S ← S \ {p}
19     end
20   end
21 end
22 end
```



- **Adaptation is still slow in computation!**
- **(Selected) Improvements**
  - Finding core and dead features quickly
  - Early identification of invalid t-sets
  - Parallelization
  - and several more...

# Vending Machine and ICPL runtimes

- VM has 12 valid variants
- $t = 2$ , ICPL calculates CA of size 6
- 50% testing time saved
- ICPL can handle large-scale SPLs
- 2-wise with „normal“ hardware possible
- Easily over 90% variant reduction

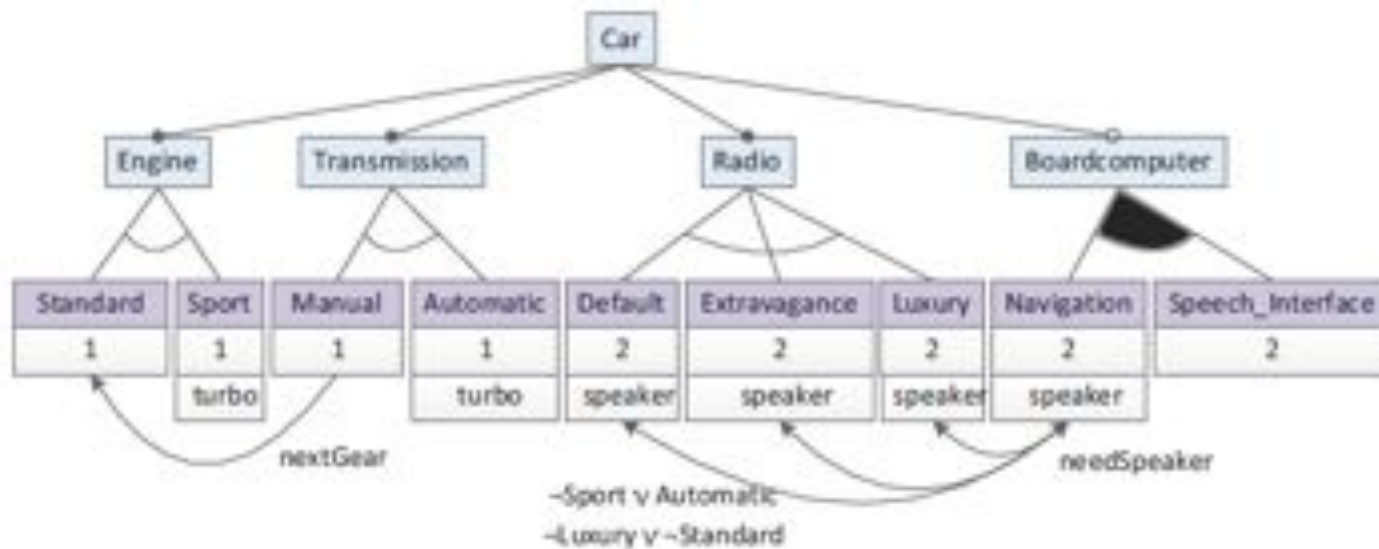
Feature\Product	0	1	2	3	4	5
Coffee	X	X	X	X	X	X
Beverage	X	X	X	X	X	X
2€		X	X	X	X	
Change		X			X	
Tea		X	X			X
Restock Cups		X		X		X
1€	X	X	X	X	X	X
Coins	X	X	X	X	X	X
Vending Machine	X	X	X	X	X	X

- Even with ICPL: Calculation time can be several hours

Feature Model	Features	Constraints	2-wise size	2-wise time (s)
2.6.28.6-icse11.dimacs	6,888	187,193	480	33,702
freebsd-icse11.dimacs	1,396	17,352	77	240
ecos-icse11.dimacs	1,244	2,768	63	185
Eshop-fm.xml	287	22	21	5

# Feature Annotations for More Efficient Combinatorics

- Annotate features with **shared resources**, **communication links**, **testing priorities**
- Use additional information for combinatorial testing
- **Consequence**: Even lesser variants to test and shorter computation time

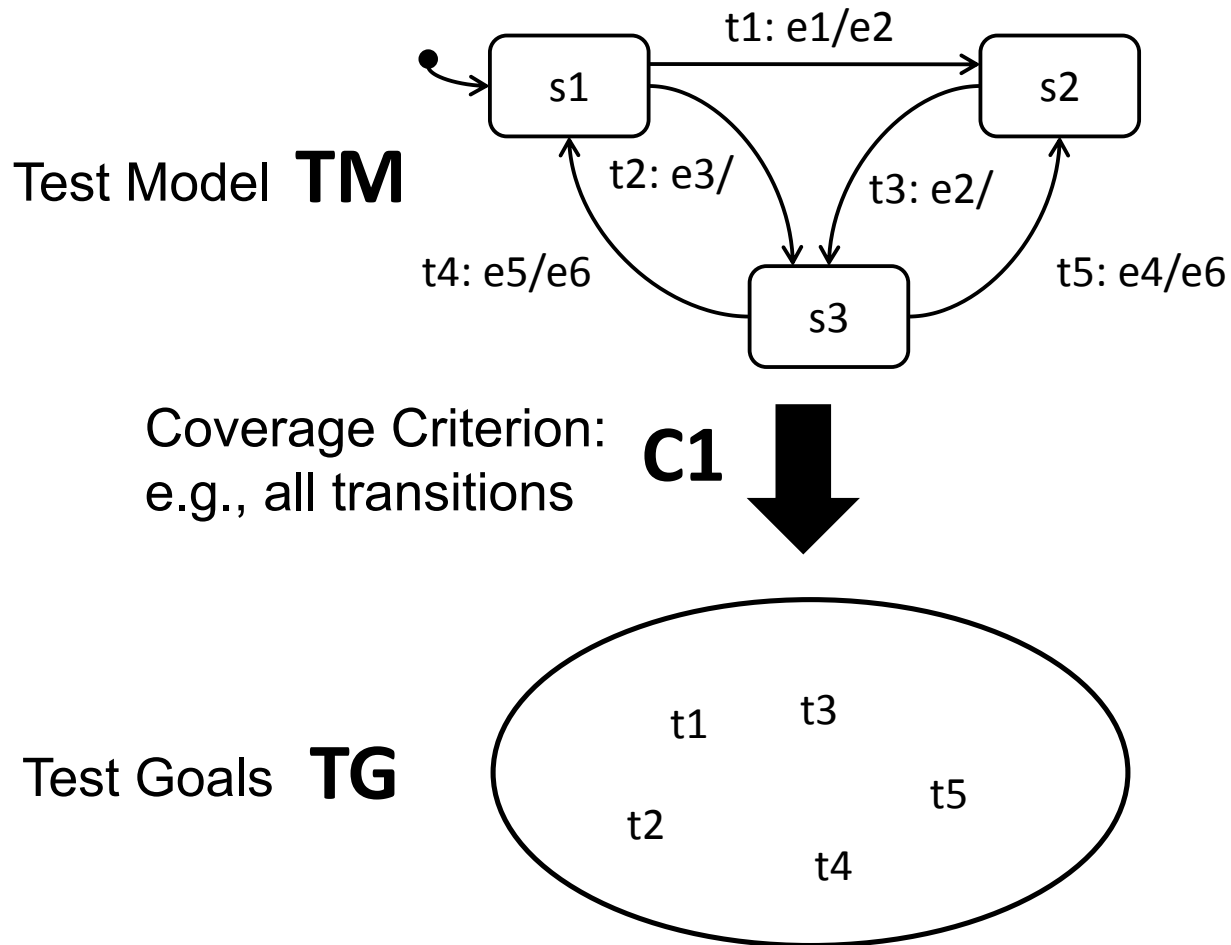


Kowal, M., Schulze, S., Schaefer, I.: Towards Efficient SPL Testing by Variant Reduction. In: VariComp. pp. 1–6. ACM (2013)

# Regression-based SPL Testing

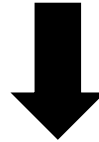


# Model-based Testing - Procedure

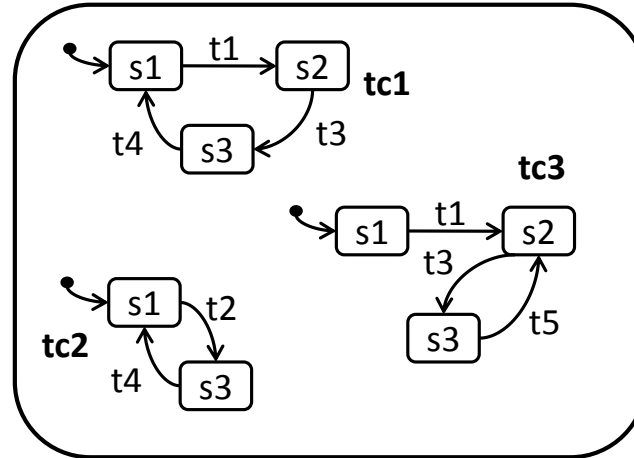


# Model-based Testing – Procedure (2)

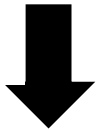
## Test Case Generation



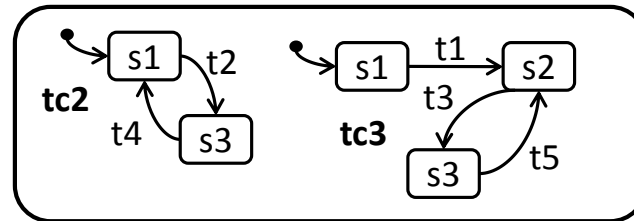
Test Suite **TS**



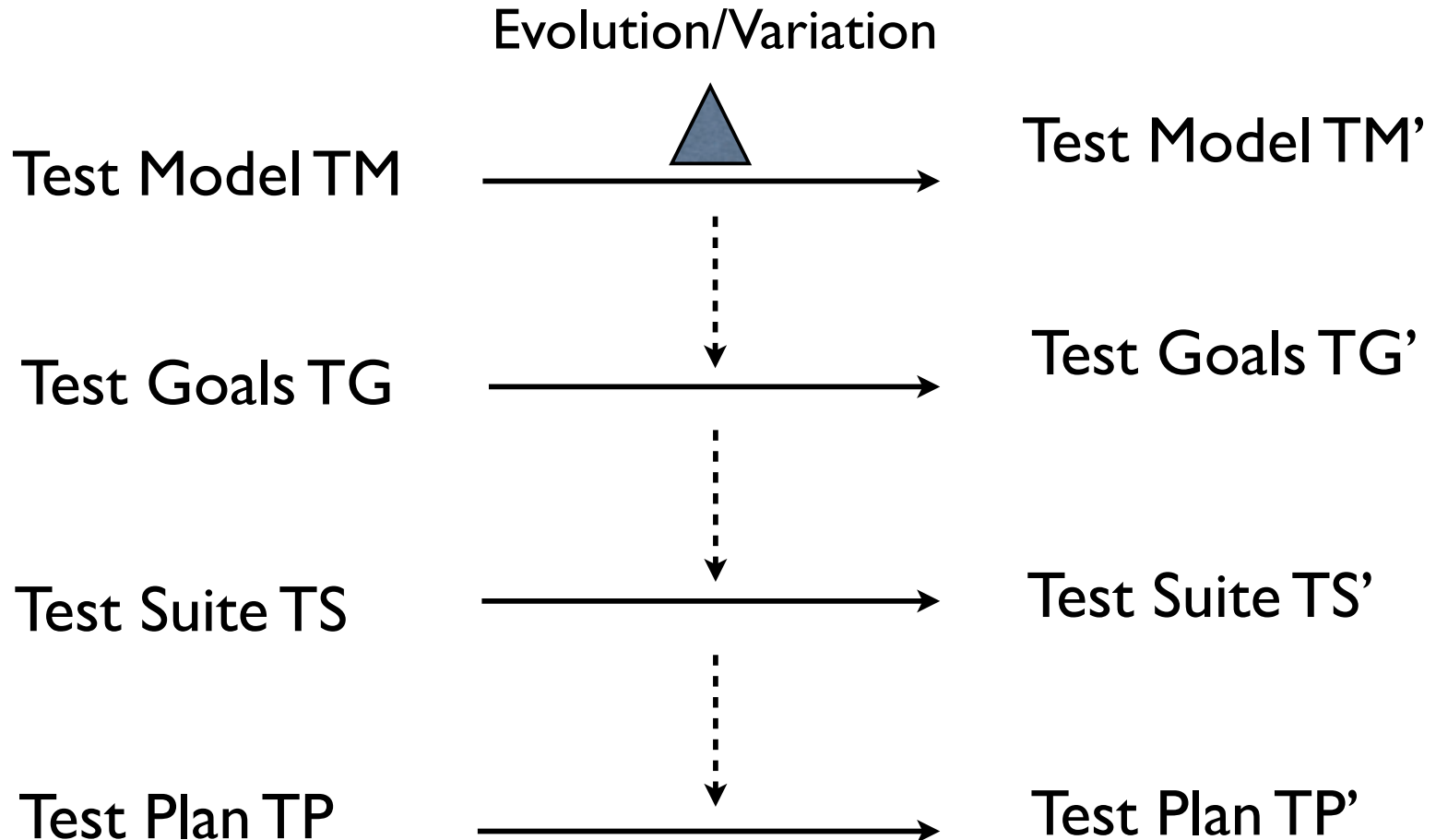
## Test Selection



Test Plan **TP**



# Incremental Model-based Testing



# Delta-Modeling of Variant-Rich Systems



- Product for valid feature configuration.
- Developed with Standard Techniques
- Modifications of Core Product.
- Application conditions over product features.
- Partial ordering for conflict resolution.



# Delta-Modeling - Background

## Instances of Delta-Languages:

- Software architectures (Delta-MontiArc)
- Programming languages (Delta-Java)
- Modeling languages (Delta-Simulink, Delta-State Machines, Deltarx)

## Advantages of Delta-Modeling:

- Modular and flexible description of change
- Intuitively understandable and well-structured
- Traceability of changes and extensions
- Support for proactive, reactive and extractive SPLE



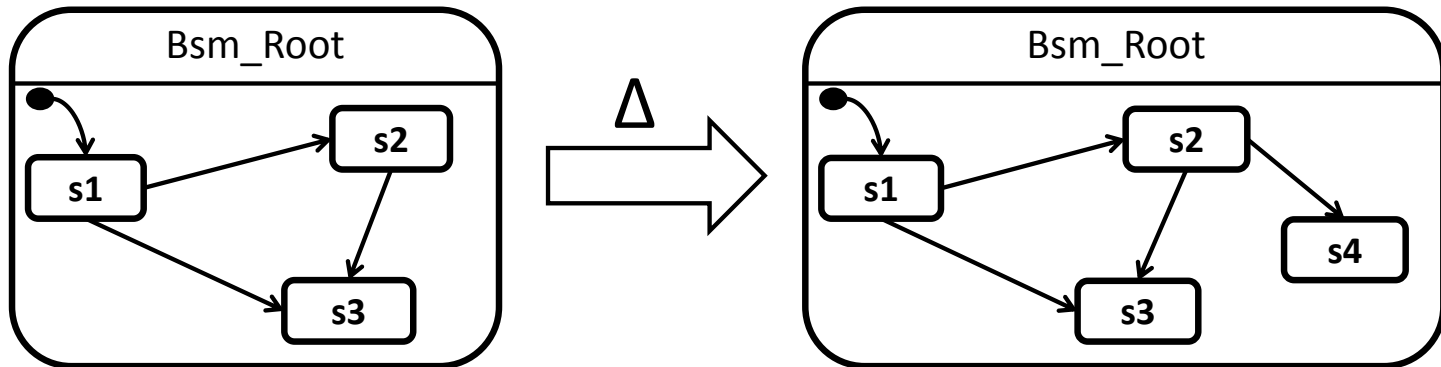
# Delta-oriented Testing approaches

- Based on delta languages and modeling techniques, different testing approaches can be defined [Lity13]
- **Goal:** Reduce regression testing effort by only testing differences between products and not every product as a whole
- **Deltas on variable test-models:**
  - Statemachines
  - Architectures
  - Activity Diagrams
- **Deltas on requirements** in natural language

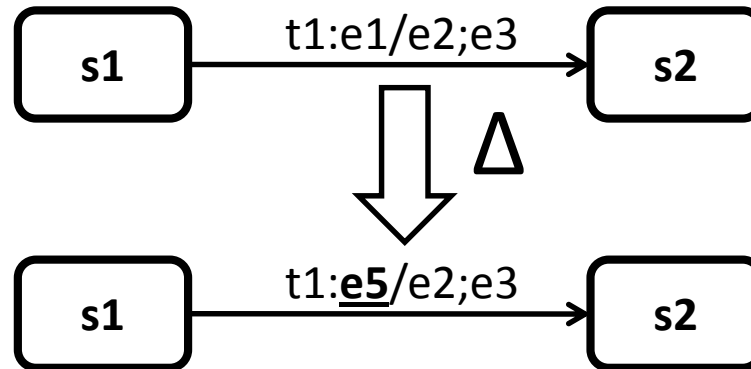


# Delta-oriented Test Models (Examples)

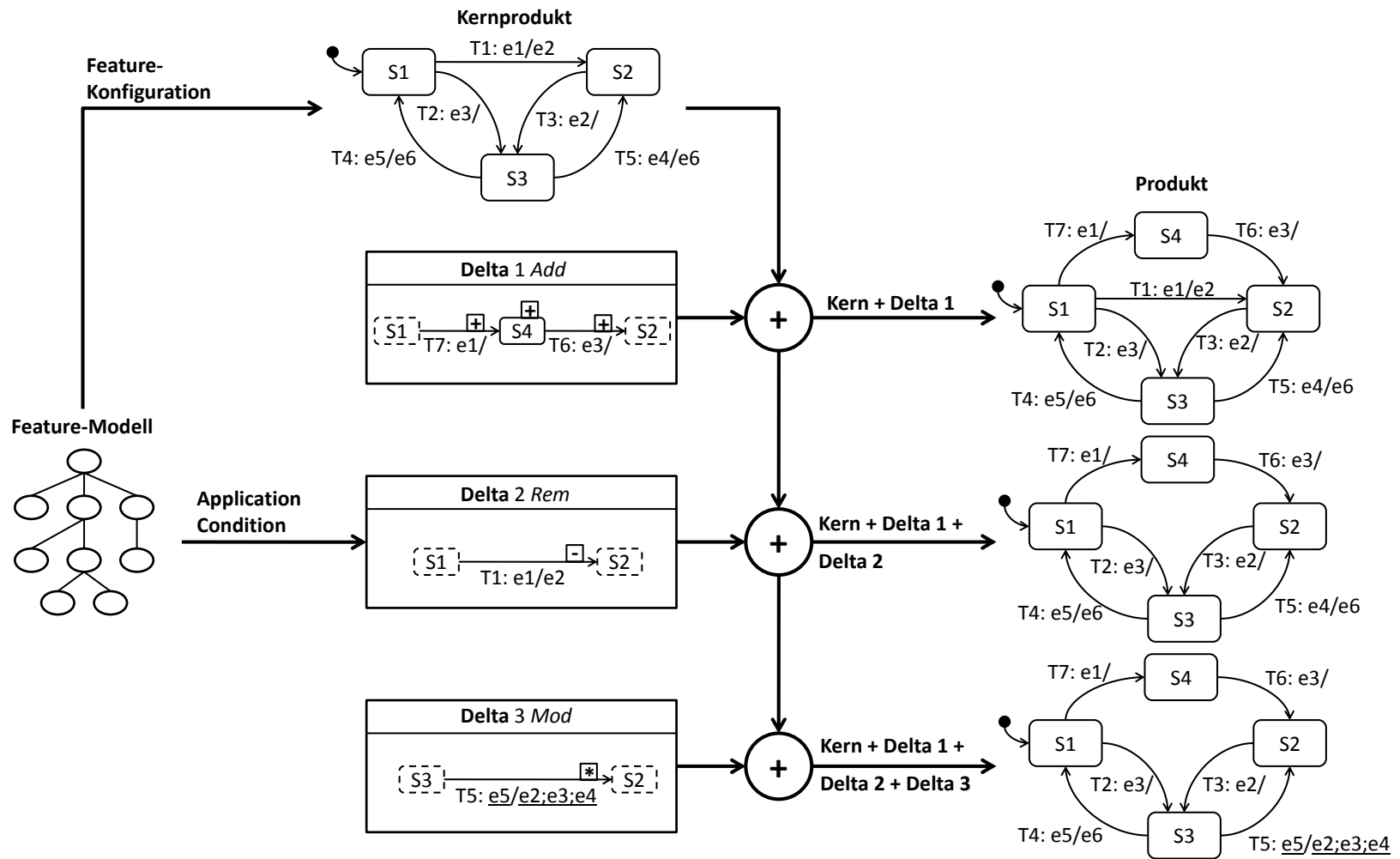
Adding a state to a State Machine:



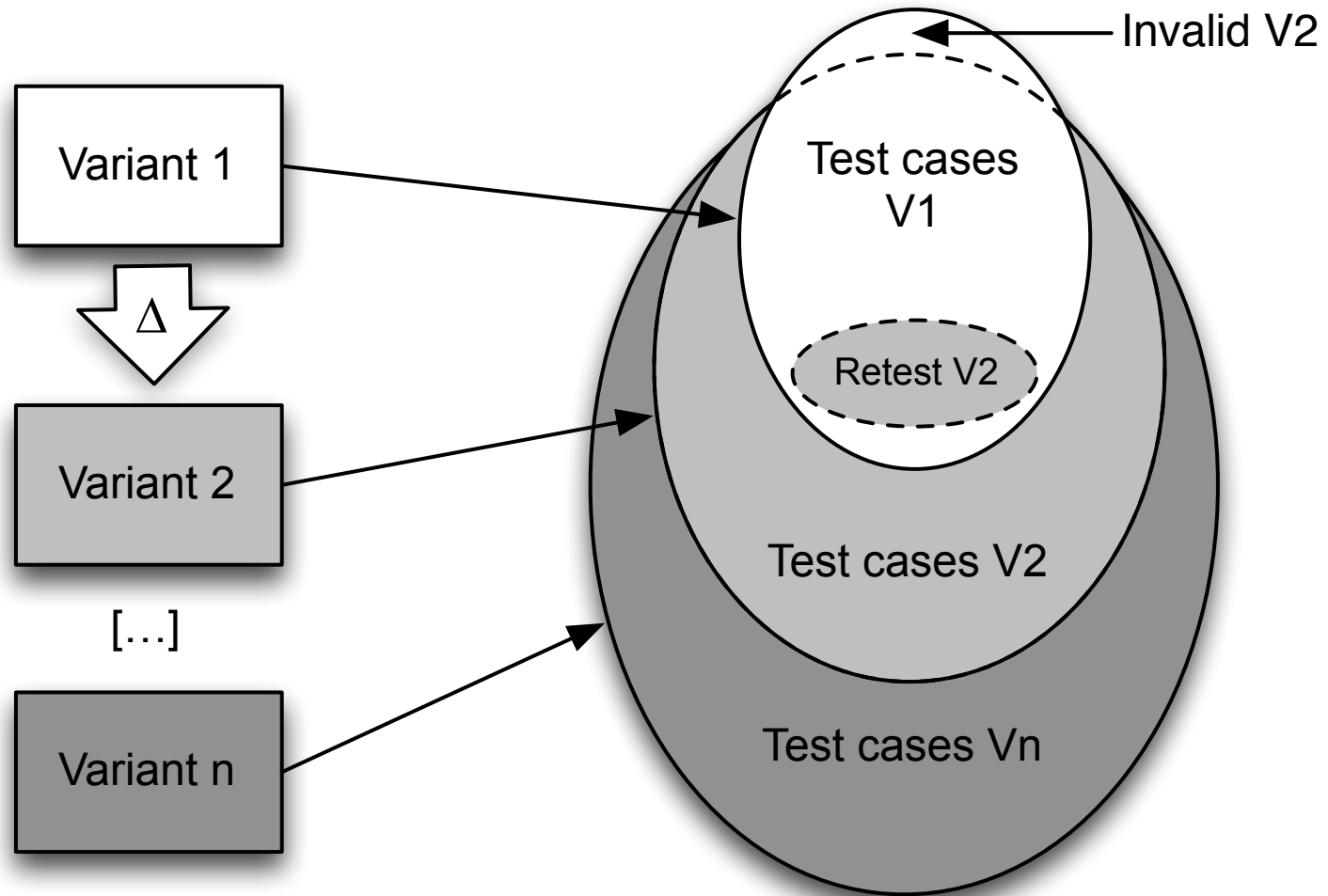
Changing the transition labels:



# Delta-oriented Test Modeling



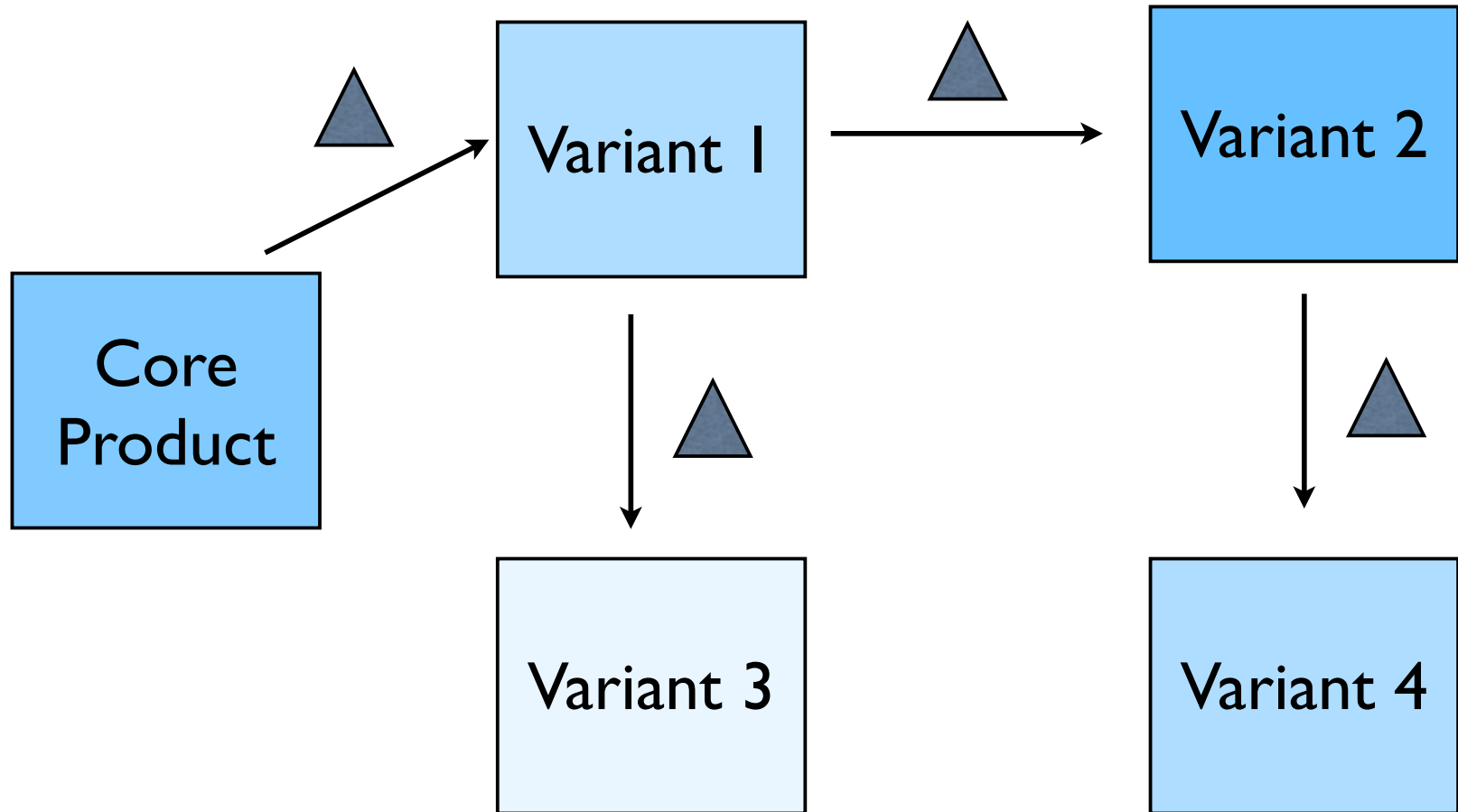
# Classification of Test Cases by Delta-Analysis



# Delta Testing - Procedure

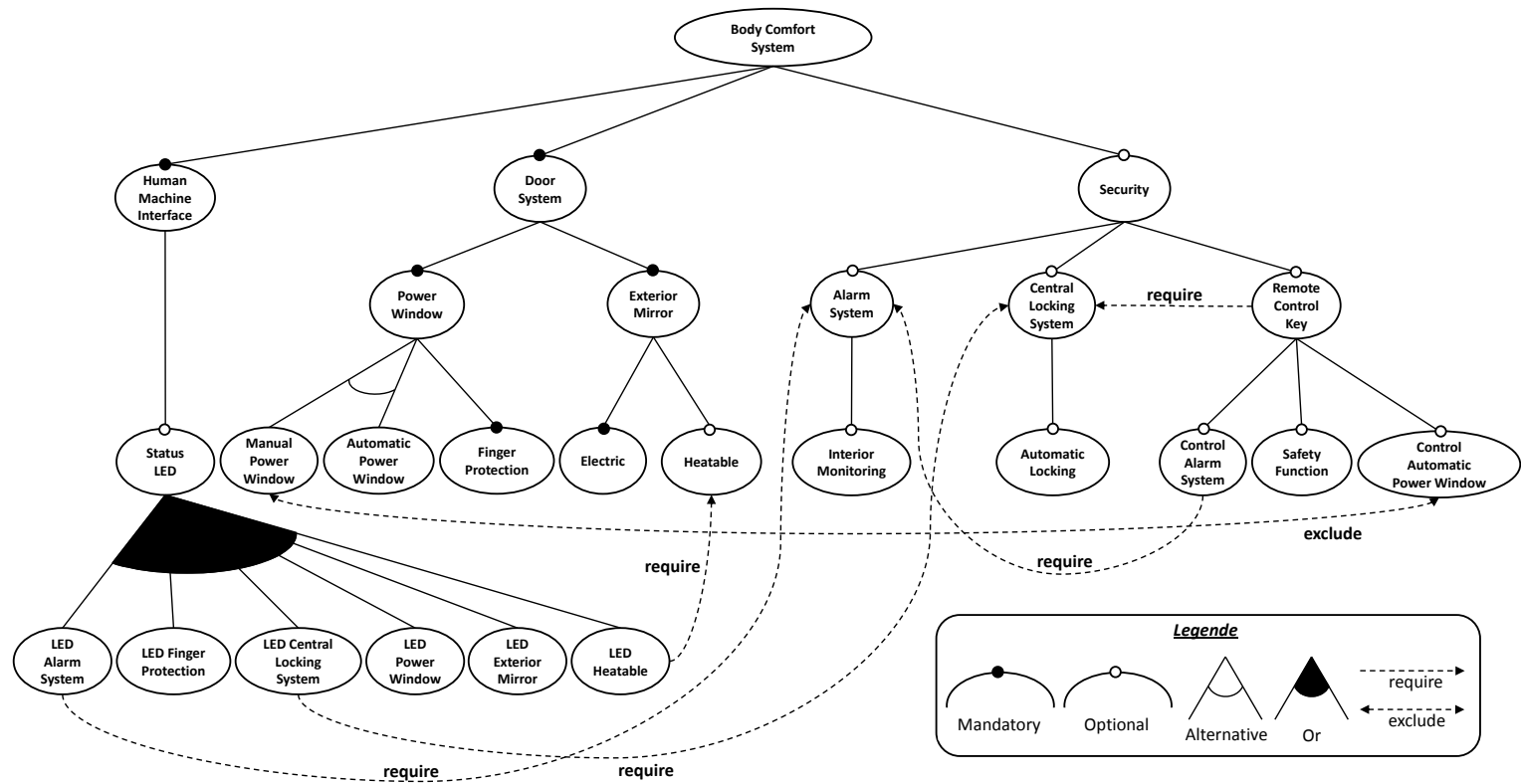
0. Fully test first product variant
1. Generate test cases for subsequent variants
  - Still valid and reuseable test cases?
  - Invalid test cases?
  - New test cases?
2. Selection of test cases by delta analysis:
  - Always test new test cases
  - Select subset of reuseable test cases for re-test
3. Optionally minimize resulting test suite by redundancy elimination

# Delta-Testing Strategy



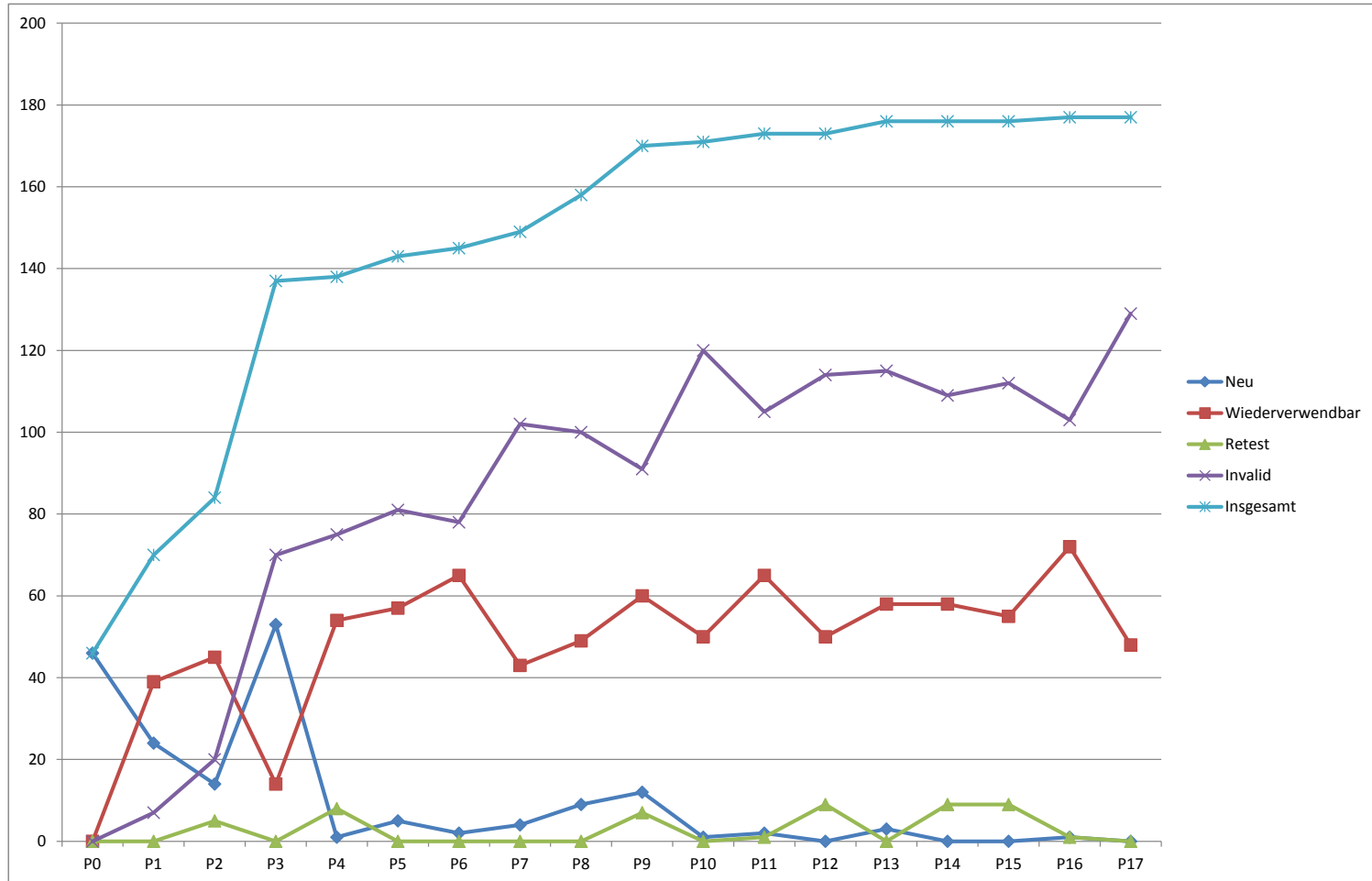
# Case Study – Body Comfort System 2

28 Features, 11616 Product Variants, 1 Core Product, 40 Deltas  
 16 Products for Pair-Wise Feature Coverage

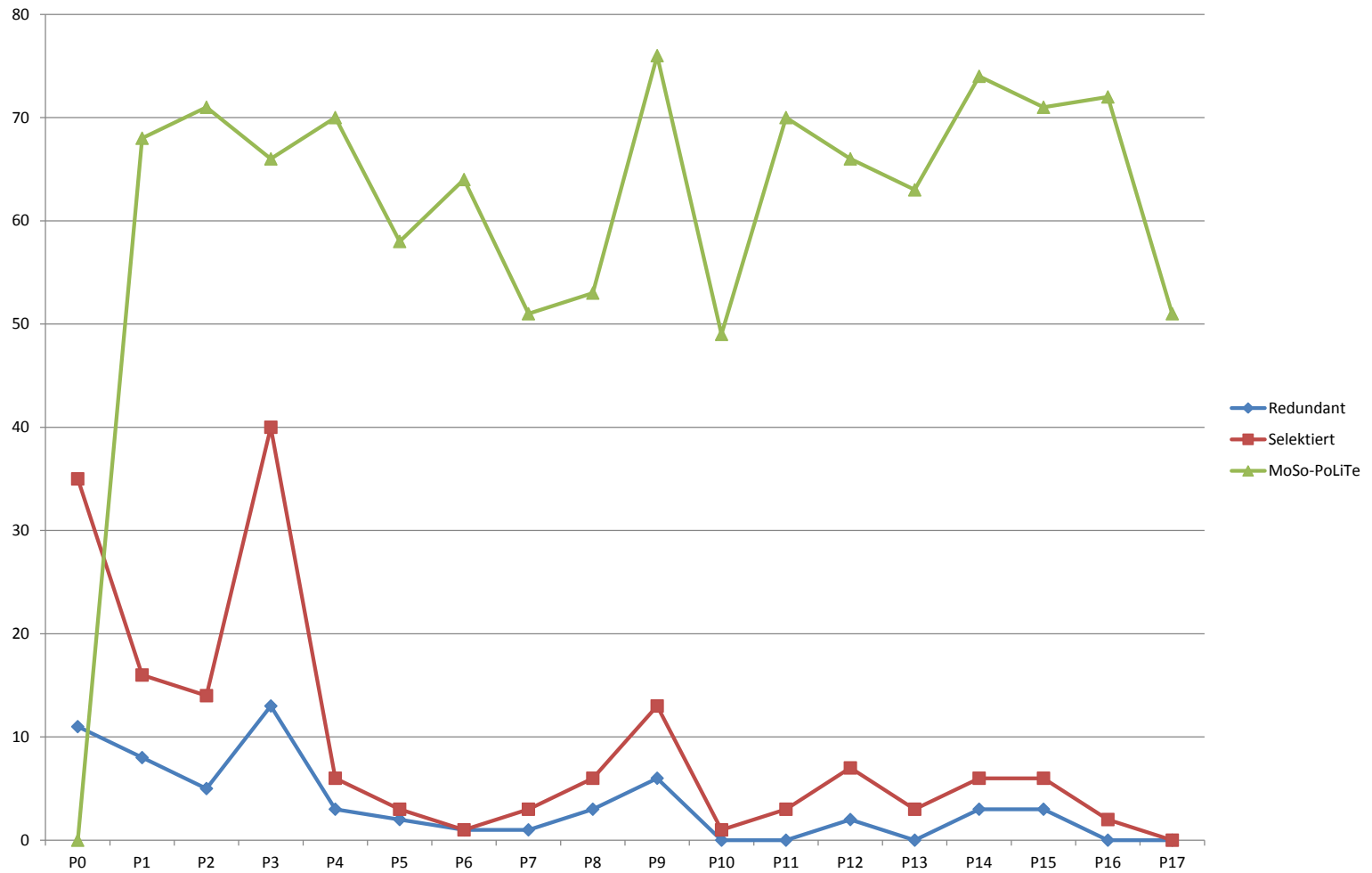




# Case Study BCM 2 – Delta-Testing Results



# Case Study BCM 2 – Delta-Testing Results (2)



# Requirements-Based Delta-oriented Testing

## Requirements

### BCS\_R1

If an object is detected in the window (window pressure  $P >$  threshold), activate the finger protection to prevent the power window from moving any further.

### BCS\_R2

If the central locking system is activated and the power window is not in the top position, move the power window up, until it reaches the top position.

### BCS\_R3

If the move down button for the power window is pressed and there is no Central locking system, move the power Window down. Otherwise, only move down if the central locking system is deactivated

**BCS\_R3V1**  
without CLS

**BCS\_R3V2**  
with CLS

### BCS\_R4

After the move up button has been tapped shortly ( $< 1$  sec), the power window moves automatically up until it reaches the top position and then the movement stops.

...

BCS\_Rn

## Test cases

### BCS\_TC1

Precondition: Window is open and an object is within the window  
Action: Press move up button  
Expected Result: Window moves up, until it reaches the objects and stops

### BCS\_TC2

Precondition: CLS is activated & power window is not in top position  
Action: Press move up button  
Expected Result: Power window moves to the top position and stops

### BCS\_TC3

Precondition: No CLS installed  
Action: Press move down button  
Expected Result: Power window moves to the bottom position and stops

### BCS\_TC4

Precondition: CLS installed and deactivated  
Action: Press move down button  
Expected Result: Power window moves to the bottom position and stops

### BCS\_TC5

Precondition: Power window is at bottom position  
Action: Press move up button for less then 1 second  
Expected Result: Power window moves to the top position and stops

...

BCS\_TCn

# Possible Strategies for Re-Test Selection

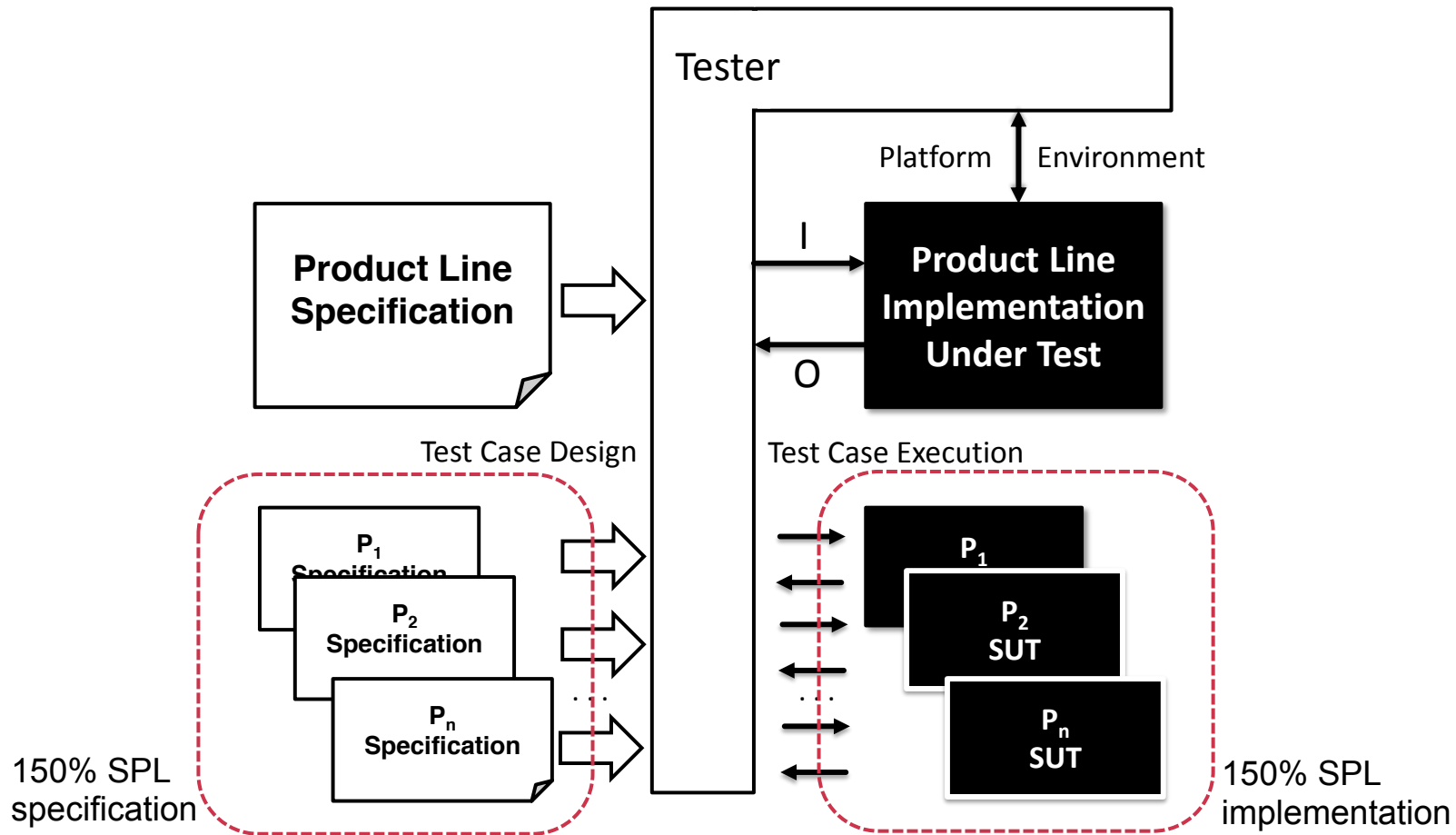
- Manually by test engineer
- (Semi-)Automatical classification of test cases into variants
- Formulation of requirements in delta-sets with linking of test cases to requirements
- Model-based impact analysis of changes by delta analysis



# Family-based SPL Testing



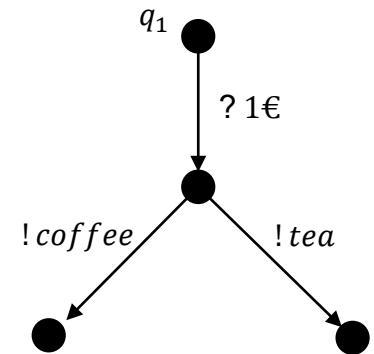
# Software Product Line Testing



# Meaning of Specifications

Implementation freedom in single system IOCO testing

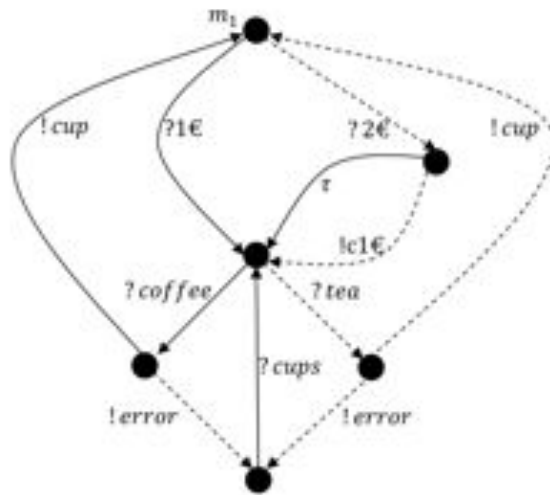
- The implementation must show **at least one** specified output behavior for specified input behaviors
- The implementation may show **arbitrary output behaviors** for unspecified input behaviors



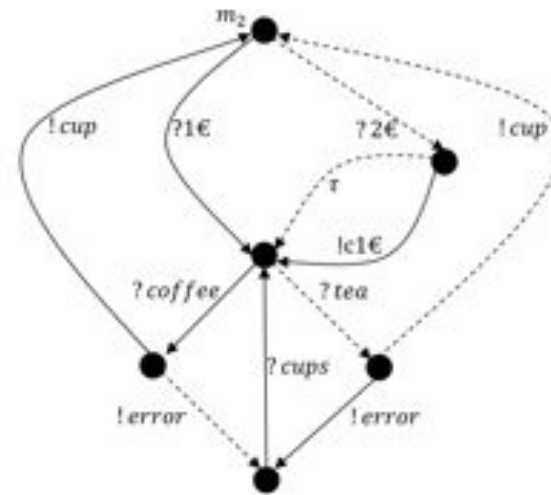
Implementation variability in SPL IOCO testing

- Distinction between **mandatory** and **possible** input/output behaviors
- SPL specification with explicit transition **modality**

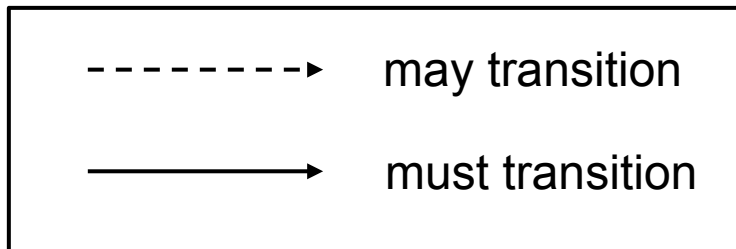
# Modal I/O Transition Systems



(a)



(b)





Modal I/O Labeled Transitionsystem:  $(Q, q_0, I, U, \rightarrow_{\diamond}, \rightarrow_{\square})$ , where

- $Q$  is a countable set of states,
- $q_0 \in Q$  is the initial state,
- $I$  and  $U$  are disjoint sets of input actions and output actions,
- $\rightarrow_{\diamond} \subseteq Q \times \mathit{act} \times Q$  is a labeled may-transition relation, and
- $\rightarrow_{\square} \subseteq Q \times \mathit{act} \times Q$  is a labeled must-transition relation.

# Syntactical Consistency of Transition Modality

Mandatory behaviors are always also possible:

$$\rightarrow_{\square} \subseteq \rightarrow_{\diamond}$$

# Modal Trace Semantics

The set of modal traces of an MTS  $m$  is defined as

$$Tr_{\gamma}(m) := \{\sigma \in (I \cup U)^* \mid \exists s \in Q : q_0 \xrightarrow{\sigma}_{\gamma} s\} \quad \text{where } \gamma \in \{\square, \diamond\}$$

From syntactical consistency of MTS it follows that

$$Tr_{\square}(s) \subseteq Tr_{\diamond}(s)$$

# Modal IOR

Modal I/O Conformance holds iff

- all **possible** behaviors of a product line implementation are **allowed** by the specification
- all **mandatory** behaviors of a product line implementation are **required** by the specification

Modal Refinement I/O Conformance holds iff the product line implementation shows

- **at least** all **mandatory** behaviors
- **at most** all **allowed** behaviors

of the product line specification.

# Modal IOCO

Let  $s, i$  be an MTS, where  $i$  is may-input-enabled.

$i \text{ mioco } s : \Leftrightarrow$

1.  $\forall \sigma \in \text{Straces}_{\diamond}(s) : \text{Out}_{\diamond}(i \text{ after}_{\diamond} \sigma) \subseteq \text{Out}_{\diamond}(s \text{ after}_{\diamond} \sigma)$  and
2.  $\forall \sigma \in \text{Straces}_{\square}(i) : \text{Out}_{\square}(i \text{ after}_{\square} \sigma) \subseteq \text{Out}_{\square}(s \text{ after}_{\square} \sigma)$ .

$i \text{ mioco}_{\leq} s : \Leftrightarrow$

1.  $\forall \sigma \in \text{Straces}_{\diamond}(s) : \text{Out}_{\diamond}(i \text{ after}_{\diamond} \sigma) \subseteq \text{Out}_{\diamond}(s \text{ after}_{\diamond} \sigma)$  and
2.  $\forall \sigma \in \text{Straces}_{\square}(i) : \text{Out}_{\square}(s \text{ after}_{\square} \sigma) \subseteq \text{Out}_{\square}(i \text{ after}_{\square} \sigma)$ .

# Conclusion

- Describing and Managing Variant-rich Systems
- Testing Strategies for Software Product Lines
  - Sample-based Testing of SPLs
  - Regression-based Testing of SPLs
  - Family-based Testing of SPLs



# Literature

- [BCS12] - S. Lity, R. Lachmann, M. Lochau, I. Schaefer: *Delta-oriented Software Product Line Test Models - The Body Comfort System Case Study*, Technische Universität Braunschweig, 2012
- [Kang90] - Kyo C. Kang, Sholom G. Cohen, James A. Hess, William E. Novak, A. Spencer Peterson - *Feature-Oriented Domain Analysis (FODA) Feasibility Study*, Technical Report, 1990
- [Lity13] - S. Lity, R. Lachmann, M. Lochau, M. Dukaczewski, I. Schaefer: *Delta-orientiertes Testen von variantenreichen Systemen*, ObjektSpektrum, 2013
- Malte Lochau, Sven Peldszus, Matthias Kowal, Ina Schaefer: Model-Based Testing. SFM 2014: 310-342